

<b>Notice of References Cited</b>	Application/Control No. 10/604,891	Applicant(s)/Patent Under Reexamination TANAKA, TAKUJI	
	Examiner Eugene Lee	Art Unit 2815	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,468,877 B1	10-2002	Pradeep et al.	438/421
	B	US-6,143,611 A	11-2000	Gilton et al.	438/279
	C	US-5,789,298	08-1998	Gardner et al.	438/286
	D	US-6,706,605 B1	03-2004	Ekbote et al.	438/305
	E	US-6,180,988 B1	01-2001	Wu, Shye-Lin	257/410
	F	US-6,051,861 A	04-2000	Togo, Mitsuhiro	257/340
	G	US-6,596,598 B1	07-2003	Krivokapic et al.	438/301
	H	US-6,251,737 B1	06-2001	Lee, Tong-Hsin	438/307
	I	US-5,545,578 A	08-1996	Park et al.	438/303
	J	US-6,127,712 A	10-2000	Wu, Shye-Lin	257/410
	K	US-6,642,592 B2	11-2003	Bae et al.	257/413
	L	US-6,124,177 A	09-2000	Lin et al.	438/305
	M	US-5,714,413	02-1998	Brigham et al.	438/301

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.